# APPLICATION FOR EXTENSION OF ESCC QUALIFICATION APPROVAL

Capacitors, Microwave, Silicon, MOS, Naked Die based on Types 101M, 201M, 400M and 401M  $\,$ Component Title:

CNES Date: 30/04/2019 Page 1

Appl. No.

			RECULIVE IVICITIBET:	NILO					dic. 00/0 //20 / 0	2000		
Components (include	ling series and famil	ies) sı	ubmitted for Extension of	of Qua	lification	Approval:					1	
ESCC COMPONENT NO.	VARIANTS	RANGE OF COMPONENTS			BASED ON		1	TEST VEHICLE / S	COMPONEN' SIMILAR	Т		
5711/002	01 to 31		40V to 200 V			400M			101M104A100M			
011001									400M106A100M 400M108C680M			
		Annual Control of the										
Component N	/lanufacturer	2	Location of Mar	nufactu	ring Plant	:(s)	3				4	
Cobham Microwave			31, avenue de la Balt					Date of original qualification approval:				
			91978 Villebon-sur-Y	vette C	Cedex			Date: 15/12/2008				
								Certi	ficate Ref No. 286			
		5					6				7	
ESCC Specification Maintenance of qua			Deviations to LVT testing and Detail Specification used:						Qualification Extension Report reference and date:			
Generic: 5010	Issue: 3		No ⊠ Yes			details in E	Box		2017098652-223 dated 25/09/2017			
5 . 7			15)				2018019456-223 dated 18/01/2018 20181211476-223 dated 03/01/2019					
Detail(s): 5711/0	02 Issue: 3		Deviation from current Specifications:  No ⊠ Yes □ (Supply details)									
			No ⊠ Yes		(Supply	uetalisj						
	1000								A.B. S.		8	
Summary of procur	ement or equivalent	test r	esults during current va	lidity p	eriod in s	upport of t	his ap	plication	on (those to ESCC listed	first)		
Project Name Testing Level		LAT D			Date code	Date code			y Delivered			
Various		Chart F4B 2017 - 2018			018		>16 000					
				I			**********					
PID changes since	start of qualification	)	9	Curr	ent PID	Verified by	v:		CNES (	7LR)	10	
None							Name of Excutive Representative					
Minor* ⊠				Ref	No:	PID 302						
Major* □	*Provide details in	n box:	Issue:				Date: 18/04/2019					
51.				Rev	Date:	18/04/20	19					
	d 6 1010		1 F. Martin	)	\A === 0\	IEC /	21.0	)		4/00/2014	11	
Current Manufactui	(Name of Executive Representative) on 24/09/2014  (Date)											
_			•		Coulive K	chieseille	uve)			(Date)		
Satisfactory:	Yes ⊠		No □ Exp	plain								
	00017	DC 1	UD 0044	100								
Report Reference:	COBH-CI	RC-A	UD-2014	ul	Es	A-TE	ca	נש ב	-RP-0508)			
				-		-61			District Control of the Control of t			

#### APPLICATION FOR EXTENSION OF ESCC QUALIFICATION APPROVAL Page 2 Capacitors, Microwave, Silicon, MOS, Naked Die based on Types 101M, 201M, 400M and 401M Component title: Appl. No. CNES Executive Member: 30/04/2019 Date: 286E 12 Failure Analysis, DPA, NCCS available: No (Supply data) Ref. No's and purposes: The undersigned hereby certifies on behalf of the ESCC Executive - that the above information is correct; that the appropriate documentation has been evaluated; - that full compliance to all ESCC requirements is evidence (except as stated in box 15;) - that the reports and data are available at the ESCC Executive and therefore applies on behalf of CNES as the responsible Executive Member for ESCC qualification status to be extended to the component(s) listed herein. Date: 30/04/2019 JP. BUSSENOT (Signature of the Executive Coordinator) Continuation of Boxes above:

13

14

The audit performed on Sept. 2014 focussed on the manufacturer's isolator and circulator products. However some areas (back end, screening) and general topics (quality, organisation, ...) are common with the sicilon components manufacturing and have benefited from it.

Editorial changes: new edition of ESCC 5010 (Issue 3) and Detailed Specification ESCC (Issue 4), updated organisation chart.

Box 11:

Date:

### APPLICATION FOR EXTENSION OF ESCC QUALIFICATION APPROVAL

Capacitors, Microwave, Silicon, MOS, Naked Die based on Types 101M, 201M, 400M and 401M Component title:

**Executive Member: CNES**  Date: 30/04/2019

Page 3 Appl. No.

286E

B. Schade, Head of ESA Product Assurance and Safety Department

Non comp	pliance to ESCC requirements:			15
No.:	Specification	Paragraph	Non compliance	
Additiona noncomp		ESCC qualification or rationale for acceptability	of	16
TITE	PIO EVOLUTION  THE CATEST UPOR	IS RELATED TO THE	ADOPTION UF SPECIFICATION.	
	e Manager Disposition			17
Application / F	on Approval: Yes 🗹 No 🗆 Remarks:			
Date:			3. Qn	

### APPLICATION FOR EXTENSION OF ESCC QUALIFICATION APPROVAL

Capacitors, Microwave, Silicon, MOS, Naked Die based on Types 101M, 201M, 400M and 401M Component Title:

Executive Member:

30/04/2019

Page 4 Appl. No. 286E

18

#### ANNEX 1: LIST OF TESTS DONE TO SUPPORT EXTENSION OF QUALIFICATION

Tests conducted in compliance with:

ESCC 5010 generic specification; Chart V (for ESCC/QPL parts);
Or PID-TFD (for ESCC/QML parts)

Tests vehicle identification/description:

101M104A100M	400M106A100M
400M108C680M	

Detail Specification reference: 5711/002

Chart F4B	Test	Tick when done	Conditions	Date Code Diffusion Lot	Tested Qty	No. of Rejects	Comments if not performed. Comments on Rejection
Environmental/Mechanical Subgroups	Thermal Shock Test		ESCC 5010 Para. 9.5.2				Not required (naked die)
	Shock Test		MIL-STD-750 Test Method 2016				Not required (naked die)
	Vibration Test		MIL-STD-750 Test Method 2056				Not required (naked die)
	Constant Acceleration		MIL-STD-750 Test Method 2006				Not required (naked die)
	Seal Test		MIL-STD-750 Test Method 1071				Not required (naked die)
	Moisture Resistance		MIL-STD-750 Test Method 1021				Not required (naked die)
	Seal Test		MIL-STD-750 Test Method 1071		1		Not required (naked die)
	Electrical Measurements at Room Temp.		Table 2 of the Detail Specification				Not required (naked die)
	External Visual Inspection		ESCC Basic Specification No. 20500				Not required (naked die)
Endurance Subgroup	Operating Life	×	MIL-STD-750 Test Method 1026	1730 1805 1844	8 + 8 + 8	0	
	Electrical Measurements during Endur. Test	×	Table 6 of the Detail Specification	1730 1805 1844	8 + 8 + 8	0	
	External Visual Inspection		ESCC Basic Specification No. 20500				Not required (naked die)



### APPLICATION FOR EXTENSION OF ESCC QUALIFICATION APPROVAL

Component title:

Capacitors, Microwave, Silicon, MOS, Naked Die based on Types 101M, 201M, 400M and 401M  $\,$ 

Executive Member: **CNES**  Date: 30/04/2019

Page 5 Appl. No.

286E

Chart F4B	Test	Tick when done	Conditions	Date Code Diffusion Lot	Tested Qty	No. of Rejects	Comments if not performed. Comments on Rejection
Electrical Subgroup – Electrical Measurements	Electrical Measurements at Room Temp.		Table 2 of the Detail Specification				Not required (naked die)
	Electrical Measurements at High & Low Temp's		Table 3 of the Detail Specification				Not required (naked die)
Electrical ectrical N	External Visual Inspection		ESCC Basic Specification No. 20500				Not required (naked die)
	Special Testing		The Detail Specification				Not required (naked die)
Electrical Subgroup  - Assembly Capability Tests	Solderability Test		MIL-STD-750 Test Method 2026				Not required (naked die)
	Permanence of Marking		ESCC Basic Specification No. 24800				Not required (naked die)
Electr Cap	Terminal Strength		MIL-STD-750 Test Method 2036				Not required (naked die)
De- encapsulation Sub group	Internal Visual Inspection		ESCC Basic Specification No. 20400				Not required (naked die)
	Bond Stregth	×	MIL-STD-750 Test Method 2037	1730	4	0	
	Die Shear	×	MIL-STD-750 Test Method 2017	1730	4	0	



Additional Comments.

**Box 22** 

#### APPLICATION FOR EXTENSION OF ESCC QUALIFICATION APPROVAL

Capacitors, Microwave, Silicon, MOS, Naked Die based on Types 101M, 201M, 400M and 401M Component title:

Executive Member: **CNES** 30/04/2019 Page 7

Appl. No. 286E

## NOTES ON THE COMPLETION OF THE APPLICATION FORM FOR ESCC QUALIFICATION EXTENSION APPROVAL

	TIES ON THE COMPLETION OF THE APPLICATION FORM FOR ESCC QUALIFICATION EXTENSION APPROVAL
ENTRIES Form heading	shall indicate: - the title of the component as given in its detail specification or the name of the series, family; - the Executive Member; - the entering date; - the certificate number and its sequential suffix.
Box 1	shall provide details given in the table; in particular there shall be listed: - the variants or range of variants; - the range of components (the ESCC code is recommended to indicate the values or values range, the tolerance, the voltage, etc); the designation given in the detail specification as 'base on'; - under Test Vehicle enter either an ESCC code or the specific characteristic capable of identifying the component tested (e.g., voltage of coil for a relay); - under component similar enter a cross if relevant.
Box 2; 3 and 4	As per QPL entry; otherwise, an explanation of the changes must be supplied.
Box 5	Will show the ESCC Generic and Detail specifications, including issue number and revision letter, current at the time the tests reported were performed. If the specifications are different from those current on the date of the application, see Box 6.
Box 6	Will show the deviations from the Generic and Detail Specifications listed in Box 5, in particular deviations from testing. In case of deviations this must be listed in Box 15. In case the referenced specification in Box 5 have currently a different issue and/or revision indicate also whether the test data deviates or not from such current documents.
Box 7	Must reference the report(s) supplied in support of the application.
Box 8	Should provide the details of procurement to the full ESCC System, documentation of all of which should already have been delivered to the ESCC Executive under the terms of the relevant Generic Specification. An appropriate table has been drawn in this box.
Box 9	If the PID evolved after the Original Qualification or after the last Extension of Qualification, adequate details of such evolution shall be provided together with the reasons for the changes. Major changes shall be clearly marked.
Box 10	Identify the current PID issue status, date and actual date of verification. The date of verification of the current PID should be arranged as close as possible to the required date of extension.
Box 11	This box can be completed only after a physical visit to the plant to confirm that no unexplained changes occurred and that the practices, procedures, material, etc. used in manufacturing the components are as described in the PID. This survey shall be carried out in accordance with the requirements of ESCC Basic Specification No. 20200 and its findings shall be recorded.
Box 12	Provide details of, or reference to, any Destructive Physical Analysis (DPA) and Failure Analysis reports as well as any Nonconformance(s) (NCCS) occurred during the qualification validity period, stating if established corrective action have produced satisfactory results.
Box 13	Enter only the name of the Executive Member (i.e., CNES, DLR, ESTEC, etc.) and the signature of the responsible Executive Coordinator.
Box 14	To be used when there is a need to expand any of the boxes from 1 through 12. Identify box affected and reference the Box 14 in the relevant Box. Box 14 can be broken into 14a, 14b, etc. if several boxes have to be expanded.
Box 15	Fill in Table as requested.
Box 16	Any additional action deemed necessary by the Executive Member to bring the submitted data to a standard likely to be accepted by the ESCC Executive should be listed herein or the reason(s) to accept the noncompliance.
Box 17	All Executive Manager recommendations on the application itself, special conditions or restrictions, modifications of the QPL or QML entry, letters to the manufacturer, etc. shall be entered clearly in Box 19, signed by the representative for ESA, and dated.
Box 18	Fill in Table as requested.
Box 19	Confidential Details of PID changes including those of a confidential nature, shall be provided.
Box 20	State noncompliance with reference to specification(s) and paragraph(s). To simplify reference in Box 16 each nonconformance shall be sequentially numbered. If relevant state 'None'.
Box 21	Any additional action deemed necessary by the Executive Member to bring the submitted data to a standard likely to be accepted by the ESCC Executive should be listed herein or the reason(s) to accept the noncompliance.